# UNISONIC TECHNOLOGIES CO., LTD

5N55-LC **Power MOSFET** 

# **5A, 550V N-CHANNEL POWER MOSFET**

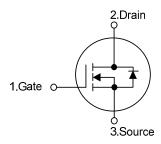
#### DESCRIPTION

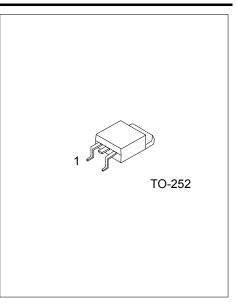
The UTC 5N55-LC is a high voltage power MOSFET designed to have better characteristics, such as fast switching time, low gate charge, low on-state resistance and high rugged avalanche characteristics. This power MOSFET is usually used in high speed switching applications of switching power supplies and adaptors.

#### **FEATURES**

- \*  $R_{DS(ON)}$  < 2.1 $\Omega$  @  $V_{GS}$  = 10V,  $I_D$  = 2.5A
- \* Fast switching capability
- \* Avalanche energy tested
- \* Improved dv/dt capability, high ruggedness

#### **SYMBOL**

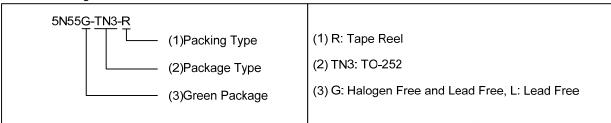




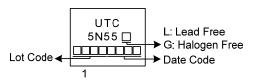
#### **ORDERING INFORMATION**

Ordering Number		Dealtons	Pin	Assignm	Doolsing		
Lead Free	Halogen Free	Package	1	2	3	Packing	
5N55L-TN3-R	5N55G-TN3-R	TO-252	G	D	S	Tape Reel	

Note: Pin Assignment: G: Gate D: Drain S: Source



#### **MARKING**



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## ■ ABSOLUTE MAXIMUM RATINGS (T<sub>C</sub> = 25°C, unless otherwise specified)

PARAMETER	SYMBOL	RATINGS	UNIT
Drain-Source Voltage	$V_{DSS}$	550	V
Gate-Source Voltage	$V_{GSS}$	±30	V
Continuous Drain Current	I <sub>D</sub>	5	Α
Pulsed Drain Current (Note 2)	I <sub>DM</sub>	10	Α
Avalanche Energy Single Pulsed (Note 3)	E <sub>AS</sub>	180	mJ
Peak Diode Recovery dv/dt (Note 4)	dv/dt	3.1	V/ns
Power Dissipation	$P_D$	52	W
Junction Temperature	$T_J$	+150	°C
Storage Temperature	T <sub>STG</sub>	-55 ~ <b>+</b> 150	°C

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress ratings only and functional device operation is not implied.

- 2. Repetitive Rating: Pulse width limited by maximum junction temperature.
- 3. L = 10mH,  $I_{AS}$  = 6.0A,  $V_{DD}$  = 50V,  $R_{G}$  = 25  $\Omega$ , Starting  $T_{J}$  = 25°C
- 4.  $I_{SD} \le 5.5A$ , di/dt  $\le 200A/\mu s$ ,  $V_{DD} \le BV_{DSS}$ , Starting  $T_J = 25^{\circ}C$

#### **■ THERMAL DATA**

PARAMETER	SYMBOL	RATINGS	UNIT	
Junction to Ambient	$\theta_{JA}$	110	°C/W	
Junction to Case	$\theta_{ m JC}$	2.5 (Note)	°C/W	

Note: The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.

## ■ **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> =25°C, unless otherwise specified)

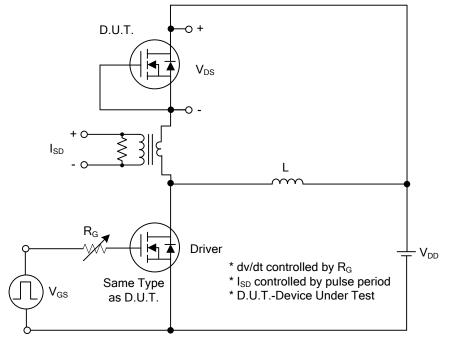
PARAMETER		SYMBOL	TEST CONDITIONS		TYP	MAX	UNIT	
OFF CHARACTERISTICS								
Drain-Source Breakdown Voltage		BV <sub>DSS</sub>	$V_{GS} = 0V, I_D = 250\mu A$	550			V	
Drain-Source Leakage Current		I <sub>DSS</sub>	V <sub>DS</sub> = 550V, V <sub>GS</sub> = 0V			10	μΑ	
Gate- Source Leakage Current	Forward	lass	$V_{GS} = 30V, V_{DS} = 0V$			100	nA	
	Reverse	I <sub>GSS</sub>	$V_{GS} = -30V, V_{DS} = 0V$			-100	nA	
ON CHARACTERISTICS								
Gate Threshold Voltage		$V_{GS(TH)}$	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2.0		4.0	V	
Static Drain-Source On-State Resistance		R <sub>DS(ON)</sub>	$V_{GS} = 10V, I_D = 2.5A$			2.1	Ω	
DYNAMIC CHARACTERISTICS								
Input Capacitance		C <sub>ISS</sub>			443		pF	
Output Capacitance		Coss	V <sub>DS</sub> =25V, V <sub>GS</sub> =0V, f=1.0 MHz		60		pF	
Reverse Transfer Capacitance		C <sub>RSS</sub>			7		pF	
SWITCHING CHARACTERISTIC	S							
Total Gate Charge (Note 1)		$Q_G$	\/ =100\/ \/ =10\/   =5.0A		17		nC	
Gate-Source Charge		$Q_GS$	V <sub>DS</sub> =100V, V <sub>GS</sub> =10V, I <sub>D</sub> =5.0A, I <sub>D</sub> =1mA (Note 1, 2)		5.6		nC	
Gate-Drain Charge		$Q_GD$	ID-IIIA (Note 1, 2)		4		nC	
Turn-On Delay Time (Note 1)		t <sub>D(ON)</sub>			6.4		ns	
Turn-On Rise Time		t <sub>R</sub>	$V_{DD}$ =100V, $V_{GS}$ =10V, $I_{D}$ =5.0A, $R_{G}$ =25 $\Omega$ (Note 1, 2)		17.5		ns	
Turn-Off Delay Time		t <sub>D(OFF)</sub>			36.8		ns	
Turn-Off Fall Time		t <sub>F</sub>			53		ns	
DRAIN-SOURCE DIODE CHARACTERISTICS AND MAXIMUM RATINGS								
Maximum Body-Diode Continuous Current		Is	I PROOF	`		5	Α	
Maximum Body-Diode Pulsed Current		I <sub>SM</sub>	118 28.			10	Α	
Drain-Source Diode Forward Voltage		$V_{SD}$	I <sub>S</sub> =5.0A , V <sub>GS</sub> =0V			1.4	V	
Body Diode Reverse Recovery Tir	me	t <sub>rr</sub>	   <sub>Is</sub> =5.0A , V <sub>GS</sub> =0V di/dt=100A/μs		228		ns	
Body Diode Reverse Recovery Charge		Qrr	13-5.0A, Ves-0V di/dt-100A/μs		1.4		μC	

Notes: 1. Pulse Test: Pulse width ≤ 300µs, Duty cycle ≤ 2%.

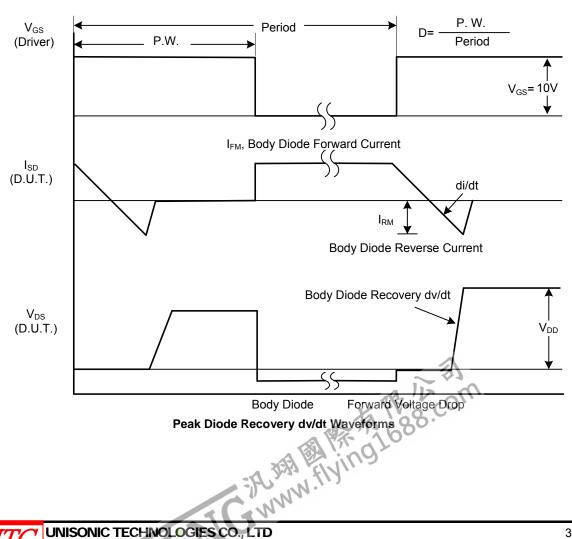
2. Essentially independent of operating temperature.

5N55-LC **Power MOSFET** 

#### **TEST CIRCUITS AND WAVEFORMS**

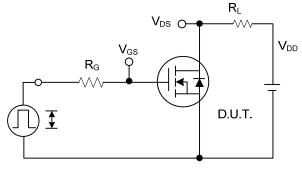


Peak Diode Recovery dv/dt Test Circuit

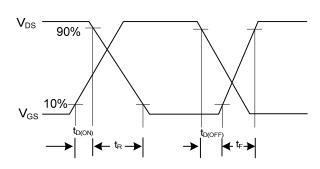


5N55-LC Power MOSFET

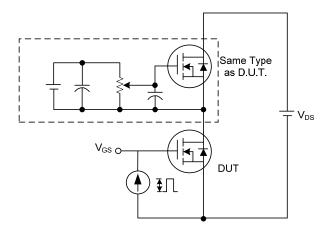
#### **■ TEST CIRCUITS AND WAVEFORMS**



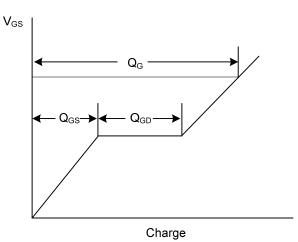
**Switching Test Circuit** 



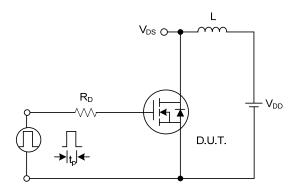
**Switching Waveforms** 



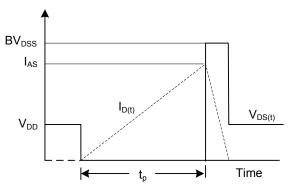
**Gate Charge Test Circuit** 



**Gate Charge Waveform** 

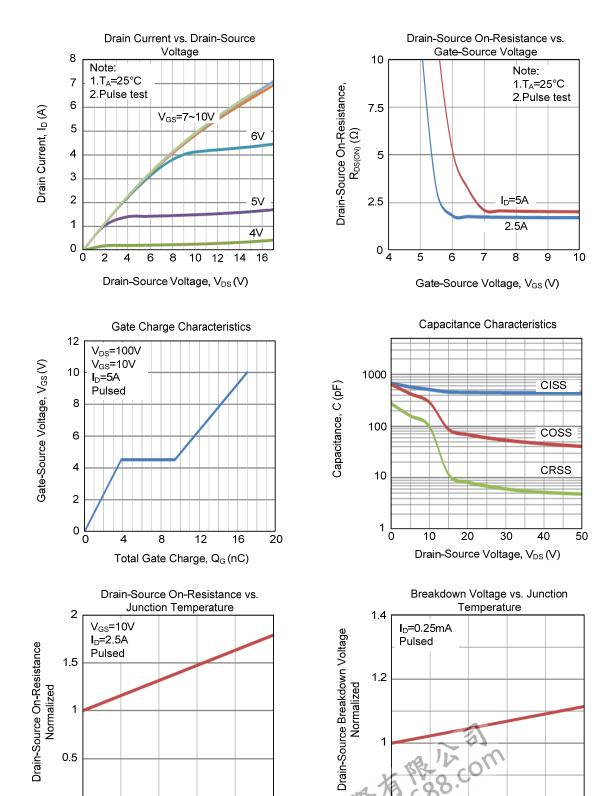


**Unclamped Inductive Switching Test Circuit** 



**Unclamped Inductive Switching Waveforms** 

#### **TYPICAL CHARACTERISTICS**



75

Junction Temperature, T<sub>J</sub> (°C)

100

125

150

0.5

0 ∟ 25

50

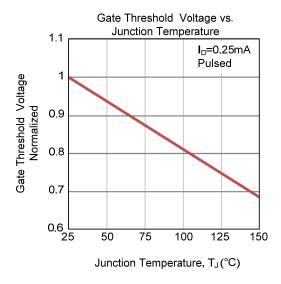
<u>150</u>

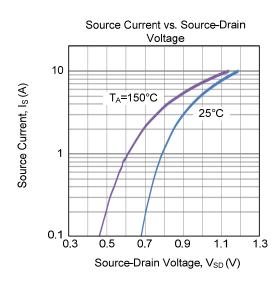
125

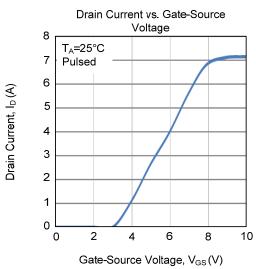
100

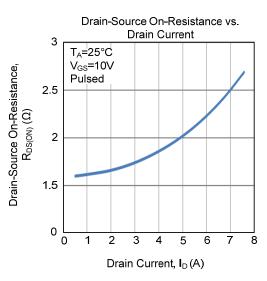
Junction Temperature, T<sub>J</sub> (°C)

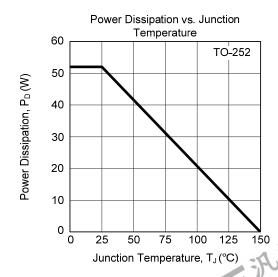
# **■ TYPICAL CHARACTERISTICS (Cont.)**

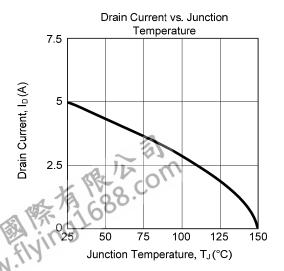




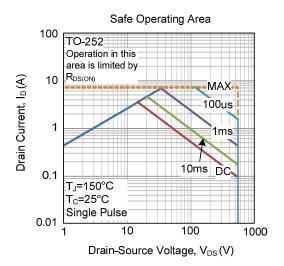








# **■ TYPICAL CHARACTERISTICS (Cont.)**



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